



# Test Report

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MOSA ELECTRONICS CORP.  
13F-6, NO. 77, SEC. 1, HSIN TAI WU ROAD, HSI-CHIH CITY,  
TAIPEI HSIEN, TAIWAN




Report on the submitted sample said to be IC MSOP 10.

Style/Item No : MS6853MG  
Sample Receiving Date : 2006/10/23  
Testing Period : 2006/10/23 TO 2006/10/30

=====  
**Test Requested** : In accordance with the RoHS Directive 2002/95/EC, and its amendment directives.

**Test Method** :  
(1) With reference to BS EN 1122:2001, Method B for Cadmium Content. Analysis was performed by ICP-AES.  
(2) With reference to US EPA Method 3050B for Lead Content. Analysis was performed by ICP-AES.  
(3) With reference to US EPA Method 3052 for Mercury Content. Analysis was performed by ICP-AES.  
(4) With reference to US EPA Method 3060A & 7196A for Hexavalent Chromium. Analysis was performed by UV/Vis Spectrometry.  
(5) With reference to US EPA 3540C for PBB/PBDE Content. Analysis was performed by GC/MS and screening via US EPA 3550C with HPLC/DAD/MS.

**Test Result(s)** : Please refer to next page(s).

  
Daniel Yen, M.R. / Operation Manager  
Signed for and on behalf of  
SGS TAIWAN LTD.

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 Test results by chemical method (Unit: mg/kg)



Test Item (s):	Method (Refer to)	Result	MDL
		No.1	
Cadmium (Cd)	(1)	n.d.	2
Lead (Pb)	(2)	n.d.	2
Mercury (Hg)	(3)	n.d.	2
Hexavalent Chromium (CrVI)	(4)	n.d.	2
<b>Sum of PBBs</b>	(5)	n.d.	-
Monobromobiphenyl		n.d.	5
Dibromobiphenyl		n.d.	5
Tribromobiphenyl		n.d.	5
Tetrabromobiphenyl		n.d.	5
Pentabromobiphenyl		n.d.	5
Hexabromobiphenyl		n.d.	5
Heptabromobiphenyl		n.d.	5
Octabromobiphenyl		n.d.	5
Nonabromobiphenyl		n.d.	5
Decabromobiphenyl		n.d.	5
<b>Sum of PBDEs (Mono to Nona) (Note 4)</b>		n.d.	-
Monobromobiphenyl ether		n.d.	5
Dibromobiphenyl ether		n.d.	5
Tribromobiphenyl ether		n.d.	5
Tetrabromobiphenyl ether		n.d.	5
Pentabromobiphenyl ether		n.d.	5
Hexabromobiphenyl ether		n.d.	5
Heptabromobiphenyl ether		n.d.	5
Octabromobiphenyl ether		n.d.	5
Nonabromobiphenyl ether		n.d.	5
Decabromobiphenyl ether	n.d.	5	
<b>Sum of PBDEs (Mono to Deca)</b>	n.d.	-	

**Test Part Description:**

NO.1 : MIXED ALL PARTS

- Note :
1. mg/kg = ppm
  2. n.d. = Not Detected
  3. MDL = Method Detection Limit
  4. Sum of Mono to NonaBDE & according to 2005/717/EC DecaBDE is exempt.
  5. "-" = Not Regulated

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\*\* End of Report \*\*